

Search Notes

Application No.

09/912,188

Examiner

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Applicant(s)

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Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	846	12/22/2004	
715	513	12/22/2004	
707	9	12/22/2004	
705	27	12/22/2004	
705	37	10/22/2005	
709	219	10/22/2005	

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search check for double patent, US-PAT, US-PGPUB, EPO, JPO, Derwent, IBM_TDB, Internet search, Plus search, EIC	12/22/2004	
Personal Digests	12/22/2004	
US-PAT, US-PGPUB, EPO, JPO, Derwent, IBM_TDB DataBase (see Search History Printout)	10/22/2005	
IEEE DataBase (see search history printout)	10/22/2005	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner